



Institut luxembourgeois de la normalisation
de l'accréditation, de la sécurité et qualité
des produits et services

ILNAS-EN IEC 61967-8:2023

Integrated circuits - Measurement of electromagnetic emissions - Part 8: Measurement of radiated emissions - IC stripline method

Integrierte Schaltungen - Messung von
elektromagnetischen Aussendungen -
Teil 8: Messung der abgestrahlten
Aussendungen - IC-

Circuits intégrés - Mesure des émissions
électromagnétiques - Partie 8: Mesure
des émissions rayonnées - Méthode de la
ligne TEM à plaques (stripline) pour

06/2023



National Foreword

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ILNAS-EN IEC 61967-8:2023

EUROPEAN STANDARD **EN IEC 61967-8**

NORME EUROPÉENNE

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English Version

**Integrated circuits - Measurement of electromagnetic emissions -
Part 8: Measurement of radiated emissions - IC stripline method
(IEC 61967-8:2023)**

Circuits intégrés - Mesure des émissions
électromagnétiques - Partie 8: Mesure des émissions
rayonnées - Méthode de la ligne TEM à plaques (stripline)
pour circuit intégré
(IEC 61967-8:2023)

Integrierte Schaltungen - Messung von
elektromagnetischen Aussendungen - Teil 8: Messung der
abgestrahlten Aussendungen - IC-Streifenleiterverfahren
(IEC 61967-8:2023)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

The text of document 47A/1152/FDIS, future edition 2 of IEC 61967-8, prepared by SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61967-8:2023.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2024-03-07
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2026-06-07

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The text of the International Standard IEC 61967-8:2023 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 61967-2 NOTE Approved as EN 61967-2

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-131	-	International Electrotechnical Vocabulary - Part 131: Circuit theory	-	-
IEC 60050-161	-	International Electrotechnical Vocabulary. Chapter 161: Electromagnetic compatibility	-	-
IEC 61000-4-20	-	Electromagnetic compatibility (EMC) - Part 4-20: Testing and measurement techniques - Emission and immunity testing in transverse electromagnetic (TEM) waveguides	EN IEC 61000-4-20	-
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions - Part 1: General conditions and definitions	EN IEC 61967-1	-



INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Integrated circuits – Measurement of electromagnetic emissions –
Part 8: Measurement of radiated emissions – IC stripline method**

**Circuits intégrés – Mesure des émissions électromagnétiques –
Partie 8: Mesure des émissions rayonnées – Méthode de la ligne TEM à plaques
(stripline) pour circuit intégré**

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